

NOT RECOMMENDED FOR NEW DESIGN **USE DMC3071LVT**



DMG6602SVT

COMPLEMENTARY PAIR ENHANCEMENT MODE MOSFET

Product Summary

Device	V _{(BR)DSS}	R _{DS(on)}	I _D T _A = +25°C
Q1	30V	60mΩ @ V _{GS} = 10V	3.4A
Qi	30 V	100mΩ @ V _{GS} = 4.5V	2.7A
Q2	-30V	95mΩ @ V _{GS} = -10V	-2.8A
Q2	-307	140mΩ @ V _{GS} = -4.5V	-2.3A

Features and Benefits

- Low On-Resistance
- Low Input Capacitance
- Fast Switching Speed
- Low Input/Output Leakage
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)
- Qualified to AEC-Q101 Standards for High Reliability

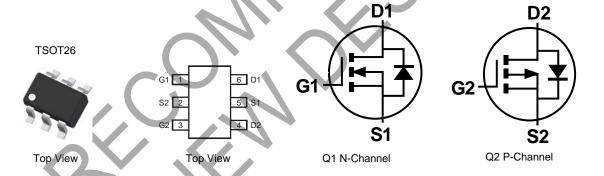
Description and Applications

This new generation MOSFET is designed to minimize the on-state resistance (R_{DS(on)}) yet maintain superior switching performance, making it ideal for high-efficiency power management applications.

- Backlighting
- DC-DC Converters
- **Power Management Functions**

Mechanical Data

- Case: TSOT26
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminals Connections: See Diagram
- Terminals: Finish—Matte Tin Annealed over Copper Leadframe. Solderable per MIL-STD-202, Method 208
- Weight: 0.013 grams (Approximate)



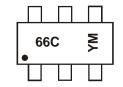
Ordering Information (Note 3)

Part Number	Case	Packaging
DMG6602SVT-7	TSOT26	3000 / Tape & Reel

Notes:

- 1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS), 2011/65/EU (RoHS 2) & 2015/863/EU (RoHS 3) compliant. 2. See https://www.diodes.com/quality/lead-free/ for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain < 900ppm bromine, < 900ppm chlorine (< 1500ppm total Br + Cl) and <1000ppm antimony compounds.</p>
 4. For packaging details, go to our website at http://www.diodes.com/products/packages.html.

Marking Information



66C = Product Type Marking Code YM = Date Code Marking Y = Year (ex: X = 2010)M = Month (ex: 9 = September)

Date Code Key

Year	2010		2011	2012		2013	2014		2015	2016		2017
Code	Х		Υ	Z		Α	В		С	D		Е
Month	Jan	Feb	Mar	Apr	May	Jun	Jul	Aug	Sep	Oct	Nov	Dec
Code	1	2	3	4	5	6	7	8	9	0	N	D



Maximum Ratings – Q1 (@TA = +25°C unless otherwise specified.)

Characterist	Symbol	Value	Unit		
Drain-Source Voltage	V_{DSS}	30	V		
Gate-Source Voltage	V_{GSS}	±20	V		
Continuous Drain Current (Note 6) V _{GS} = 10V	Steady State	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	I _D	3.4 2.7	Α
Continuous Drain Current (Note 6) V _{GS} = 4.5V	Steady State	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	I _D	2.7 2.2	Α
Maximum Continuous Body Diode Forward Current	t (Note 6)		Is	1.5	Α
Pulsed Drain Current (Note 6)	I _{DM}	25	Α		

Maximum Ratings – Q2 (@TA = +25°C unless otherwise specified.)

Characterist	С		Symbol	Value	Unit
Drain-Source Voltage	V_{DSS}	-30	V		
Gate-Source Voltage			V _{GSS}	±20	V
Continuous Drain Current (Note 6) V _{GS} = -10V	Steady State	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	Ι _D	-2.8 -2.4	А
Continuous Drain Current (Note 6) V _{GS} = -4.5V	Steady State	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	lp	-2.3 -2.1	А
Maximum Continuous Body Diode Forward Current	(Note 6)		Is	-1.5	Α
Pulsed Drain Current (Note 6)			I _D	-20	Α

Thermal Characteristics

Characteristic		Symbol	Value	Units	
Total Power Dissipation (Note 5)	$T_A = +25^{\circ}C$	D-	0.84	W	
Total Fower Dissipation (Note 5)	$T_A = +70^{\circ}C$	P_{D}	0.52	VV	
Thermal Resistance, Junction to Ambient (Note 5)	Steady State	Da	155	°C/W	
Thermal Resistance, Junction to Ambient (Note 3)	R _{OJA}	109	C/VV		
Total Power Dissipation (Note 6)	$T_A = +25^{\circ}C$	D-	1.27	W	
Total Fower Dissipation (Note 6)	$T_A = +70$ °C	P _D	0.8	VV	
Thermal Resistance, Junction to Ambient (Note 6)	Steady State	D	102		
Thermal Resistance, Junction to Ambient (Note o)	t < 10s	R _{OJA}	71	°C/W	
Thermal Resistance, Junction to Case (Note 6)		$R_{\Theta JC}$	34		
Operating and Storage Temperature Range		$T_{J_i}T_{STG}$	-55 to +150	°C	

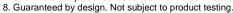
5. Device mounted on FR-4 substrate PCB, 2oz copper, with minimum recommended pad layout. 6. Device mounted on FR-4 substrate PCB, 2oz copper, with 1inch square copper plate.

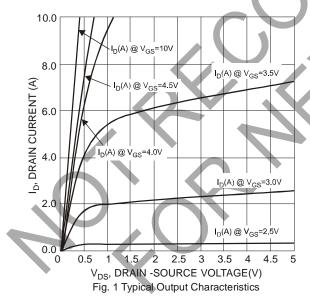


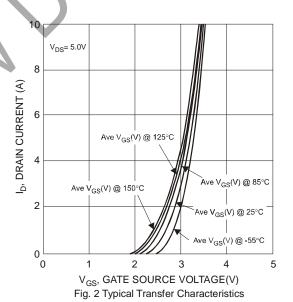
Electrical Characteristics - Q1 NMOS (@TA = +25°C unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 7)						
Drain-Source Breakdown Voltage	BV _{DSS}	30	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$
Zero Gate Voltage Drain Current	I _{DSS}	_	_	1.0	μΑ	$V_{DS} = 24V, V_{GS} = 0V$
Gate-Source Leakage	I _{GSS}	_	_	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$
ON CHARACTERISTICS (Note 7)						
Gate Threshold Voltage	$V_{GS(th)}$	1.0	l	2.3	٧	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
Static Drain-Source On-Resistance	R _{DS} (ON)	_	38	60 100	mΩ	$V_{GS} = 10V, I_D = 3.1A$
	` '		55	100		$V_{GS} = 4.5V, I_{D} = 2A$
Forward Transfer Admittance	Y _{fs}	_	4	_	S	$V_{DS} = 5V, I_{D} = 3.1A$
Diode Forward Voltage	V _{SD}	_	0.8	1	V	$V_{GS} = 0V$, $I_{S} = 1A$
DYNAMIC CHARACTERISTICS (Note 8)						
Input Capacitance	C _{iss}	_	290	400		45)/ // 2)/
Output Capacitance	Coss	_	40	80	pF	$V_{DS} = 15V, V_{GS} = 0V,$ f = 1.2MHz
Reverse Transfer Capacitance	C _{rss}	_	40	80		I = 1.2IVIH2
Gate Resistance	Rg	_	1.4	-	Ω	$V_{DS} = 0V$, $V_{GS} = 0V$, $f = 1MHz$
Total Gate Charge (V _{GS} = 4.5V)	Qg	_	4	6		$V_{DS} = 15V$, $V_{GS} = 4.5V$, $I_{D} = 3.1A$
Total Gate Charge (V _{GS} = 10V)	Q_{g}	_	9	13	nC	
Gate-Source Charge	Qgs	- (1.2		IIC	$V_{DS} = 15V$, $V_{GS} = 10V$, $I_{D} = 3A$
Gate-Drain Charge	Q_{gd}		1.5			
Turn-On Delay Time	t _{D(on)}		3	_		
Turn-On Rise Time	t _r		5			$V_{GS} = 10V, V_{DS} = 15V,$
Turn-Off Delay Time	t _{D(off)}		13	_	ns	$R_G = 3\Omega$, $R_L = 4.7\Omega$
Turn-Off Fall Time	t _f		3	7		

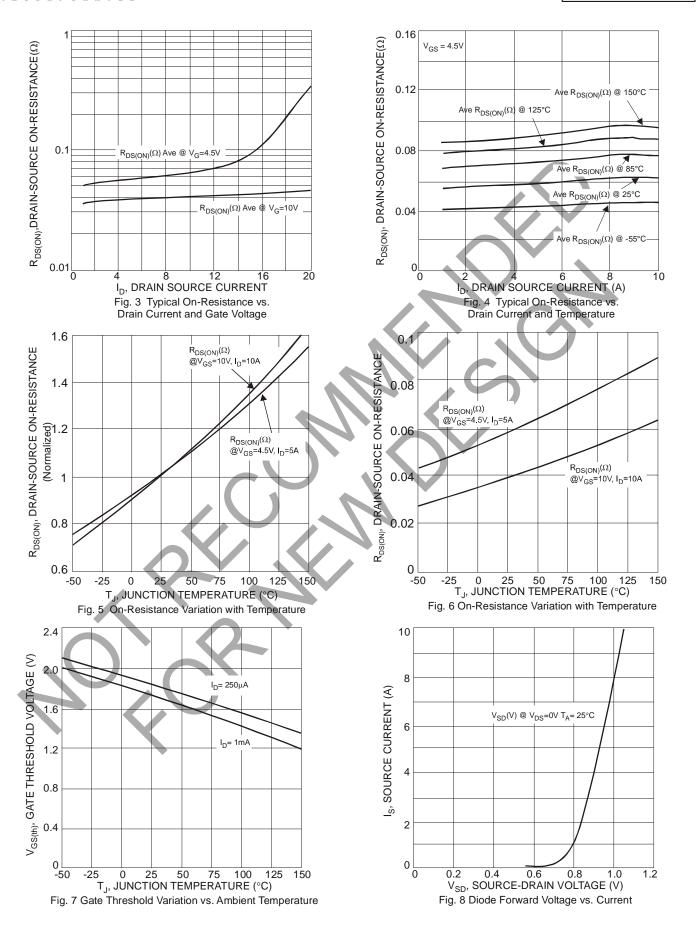
Notes: 7. Short duration pulse test used to minimize self-heating effect.



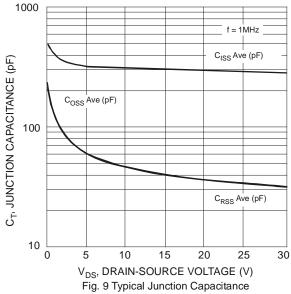












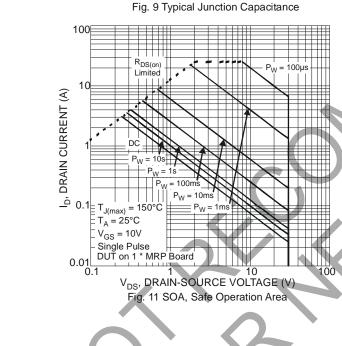
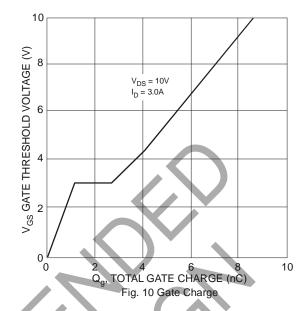


Fig. 11 SOA, Safe Operation Area



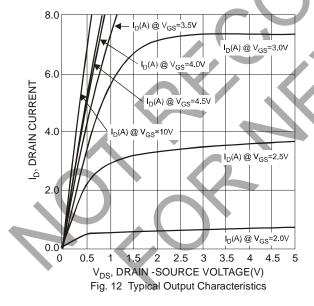


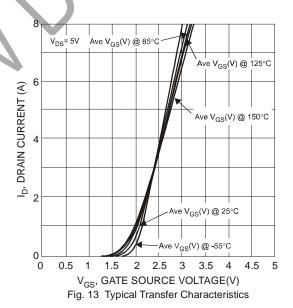
Electrical Characteristics - Q2 PMOS (@TA = +25°C unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 7)						
Drain-Source Breakdown Voltage	BV _{DSS}	-30		_	V	$V_{GS} = 0V, I_D = -250\mu A$
Zero Gate Voltage Drain Current	I _{DSS}	_		-1.0	μΑ	$V_{DS} = -24V, V_{GS} = 0V$
Gate-Source Leakage	I _{GSS}	_		±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$
ON CHARACTERISTICS (Note 7)						
Gate Threshold Voltage	V _{GS(th)}	-1.0	1	-2.3	V	$V_{DS} = V_{GS}$, $I_D = -250\mu A$
Static Drain-Source On-Resistance			73	95	mΩ	$V_{GS} = -10V$, $I_D = -2.7A$
Static Diain-Source On-INESistance	R _{DS} (ON)		99	140	11152	$V_{GS} = -4.5V, I_{D} = -2A$
Forward Transfer Admittance	Y _{fs}	1	6	_	S	$V_{DS} = -5V, I_D = -2.7A$
Diode Forward Voltage	V_{SD}	_	-0.8	-1.0	V	$V_{GS} = 0V, I_{S} = -1A$
DYNAMIC CHARACTERISTICS (Note 8)						
Input Capacitance	C _{iss}	_	350	420		15/1/1/ 01/
Output Capacitance	Coss	_	50	100	pF	$V_{DS} = -15V, V_{GS} = 0V,$ f = 1.2MHz
Reverse Transfer Capacitance	C _{rss}	_	45	80		1 = 1.2IVITZ
Gate Resistance	Rg	_	17.1	-	Ω	$V_{DS} = 0V$, $V_{GS} = 0V$, $f = 1MHz$
Total Gate Charge (V _{GS} = -4.5V)	Q_g		4	6		$V_{DS} = -15V$, $V_{GS} = -4.5V$, $I_{D} = -3A$
Total Gate Charge (V _{GS} = -10V)	Q_{g}	1	7	9	nC	
Gate-Source Charge	Q_{gs}	_	0.9		110	$V_{DS} = -15V$, $V_{GS} = -10V$, $I_{D} = -3A$
Gate-Drain Charge	Q_{gd}	7	1.2	<i>></i> -		
Turn-On Delay Time	t _{D(on)}	-//	4.8	_		
Turn-On Rise Time	t _r	1	7.3		200	$V_{GS} = -10V, V_{DS} = -15V,$
Turn-Off Delay Time	t _{D(off)}	1-1	20	_	ns	$R_G = 6\Omega$, $R_L = 15\Omega$
Turn-Off Fall Time	t _f	1	13	/ -		

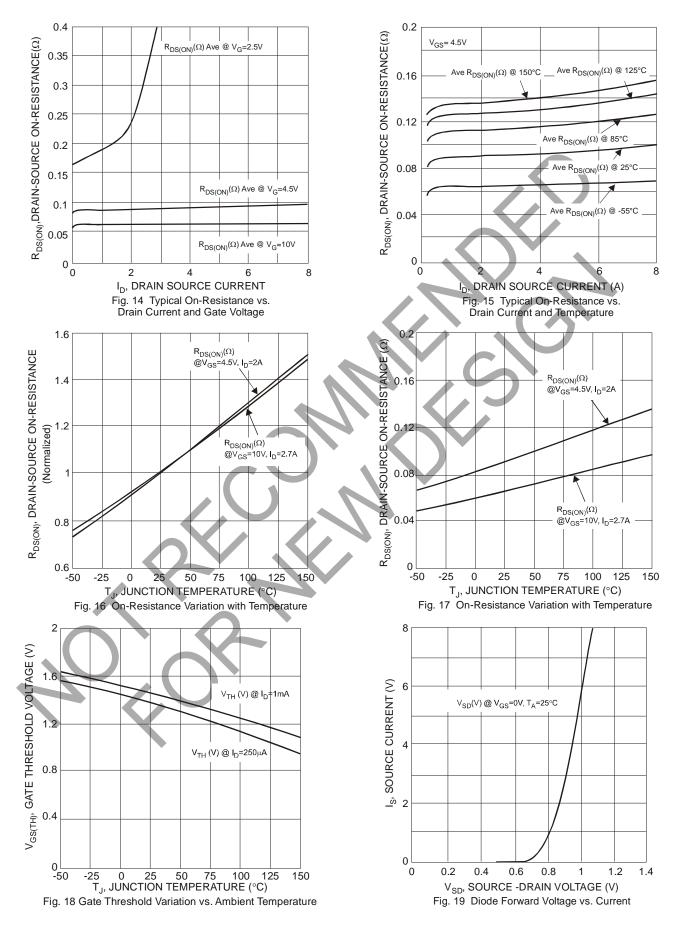
Notes:

- 7. Short duration pulse test used to minimize self-heating effect.
- 8. Guaranteed by design. Not subject to production testing.

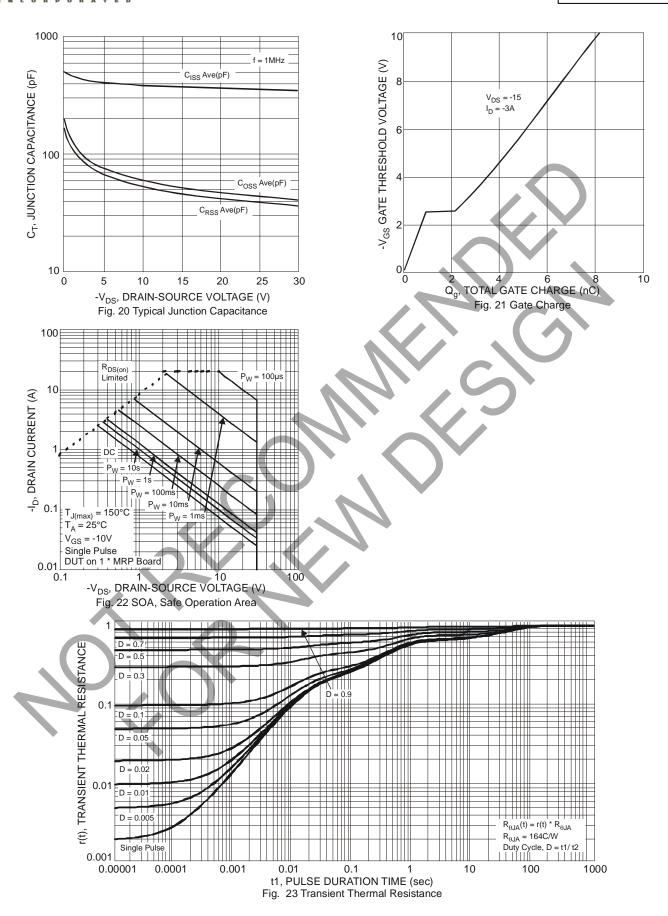








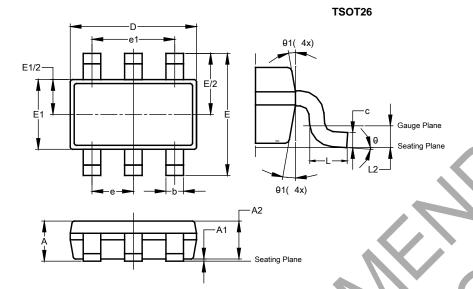






Package Outline Dimensions

Please see http://www.diodes.com/package-outlines.html for the latest version.

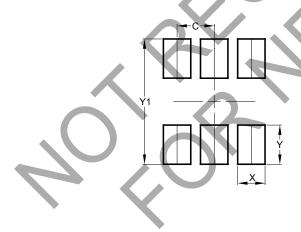


TSOT26							
Dim	Min	Max	Тур				
Α		1.00					
A1	0.010	0.100	_				
A2	0.840	0.900	-				
D	2.800	3.000	2.900				
Е	2.800 BSC						
E1	1.500 1.700 1.6		1.600				
b	0.300	0.450	-				
С	0.120	0.200	1				
е	0.950 BSC						
e1	7	.900 BS	С				
L	0.30	0.50	_				
L2	0.250 BSC						
θ	0°	0° 8° 4°					
θ1	4°	12°	=				
A	II Dimen	sions in	mm				

Suggested Pad Layout

Please see http://www.diodes.com/package-outlines.html for the latest version.





Dimensions	Value (in mm)
С	0.950
Х	0.700
Υ	1.000
Y1	3.199



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DMG6602SVT Document number: DS35159 Rev. 8 - 3